

# PFM-LNP

Rev.A2.0

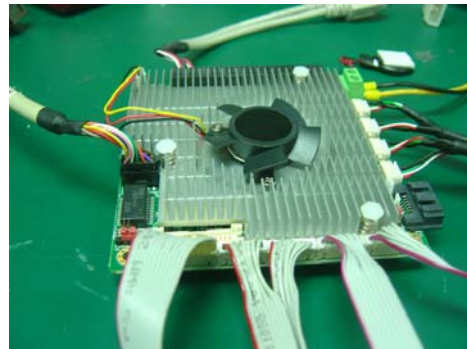
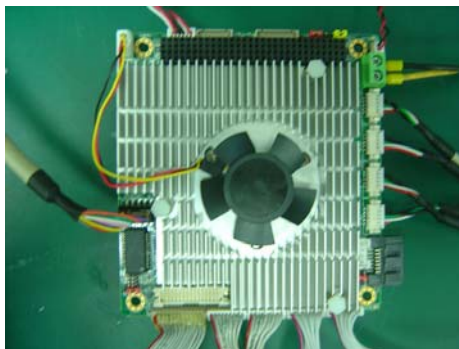
## Thermal Image Analysis Report

Summary	<input checked="" type="checkbox"/> <b>Pass</b> <input type="checkbox"/> <b>Fail</b> <input type="checkbox"/> <b>Pass with Deviation</b> <b>Comment:</b> _____			
	<b>Test Result Summary</b>			
	Critical	Major	Minor	Enhancement
Defect Found	0	0	0	0
Defect Unsolved	0	0	0	0

Issue date	Approval	Test Engineer
2014 / 03 / 21	Tom Lin	Juno cheng

## Sample Configuration & Quantity Under Test

- **Model name : PFM-LNP A2.0**
- **CPU Board : PFM-LNP Rev. A2.0**
- **CPU : Intel Atom N450/ 1.67GHz**
- **Memory : Onboard/samsung K4T1G164QF-BCE7 / 1 GB DDR2-667**
- **HDD : Toshiba 2.5" 160GB MK6476GSX (SATA)**
- **BIOS : PLN\_1 2.00 x 64 (07/16/2010)**
- **Test Software : Windows XP / Run PassMark Burn In Test 7.1 Pro**
- **Power : G-ALANTIC AD1280MB**
- **Heat Sink + Fan:**



# Thermal Image Analysis

**1. Test Date: 2014-03-21**

**2. Test Product : PFM-LNP A2.0**

**3. Test Site: QE Dept.**

**4. Temperature Measurement:**

**1. YOKOGAWA / DARWIN DA100-100-13-1D**

**2. IR Scanner: Infrared Camera**

**NIPPON AVIONICS CO., LTD.**

**Model: TVS-100**

**Date of Calibration: 2013/12/30**

**Serial Number: 0179L2746**

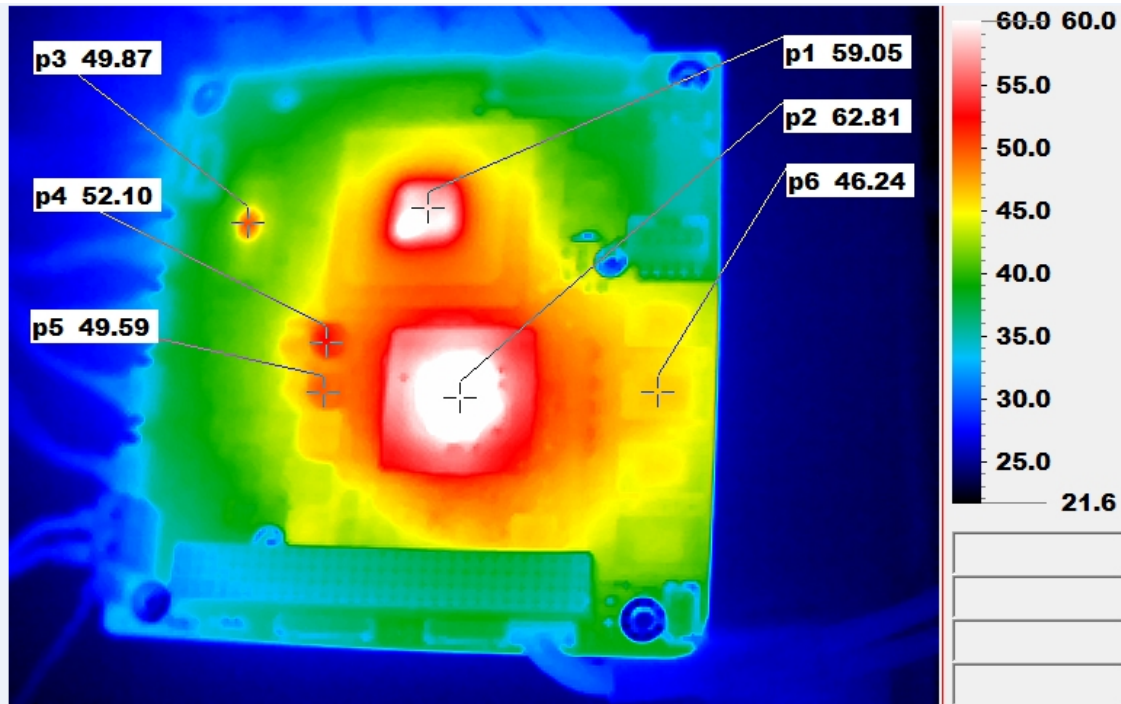
**5. Test Condition:**

**Component Side-1 (Test by DA-100 ): 25.0°C With heat sink**

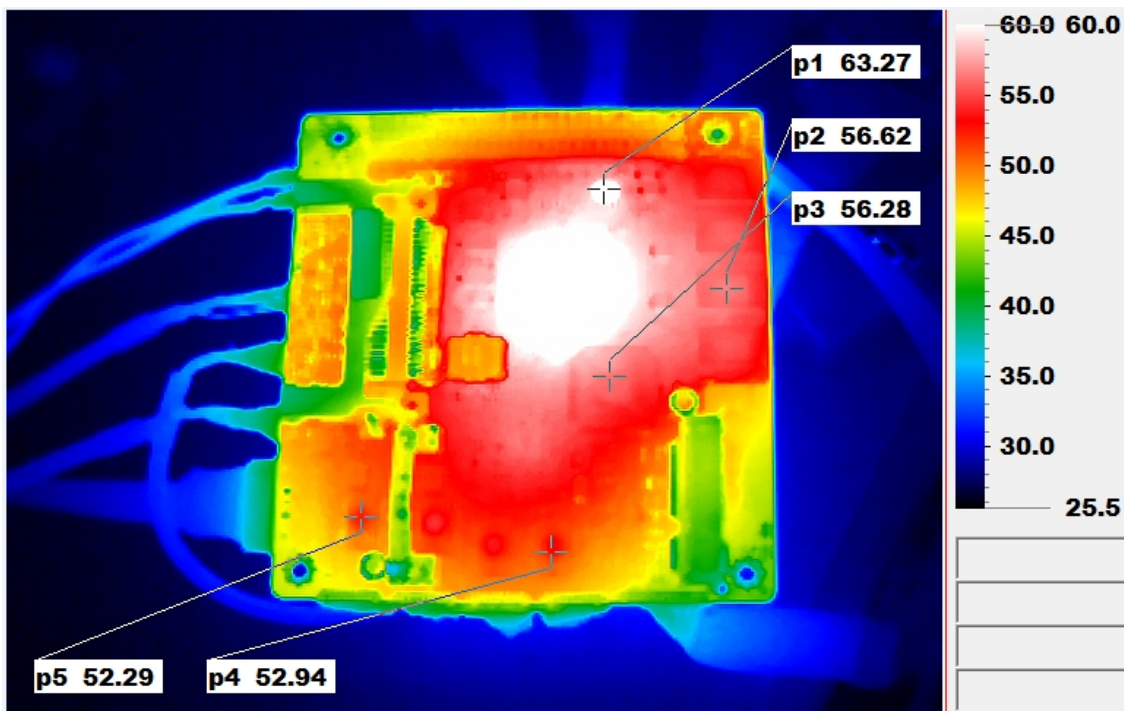
**6. Take Picture Time:**

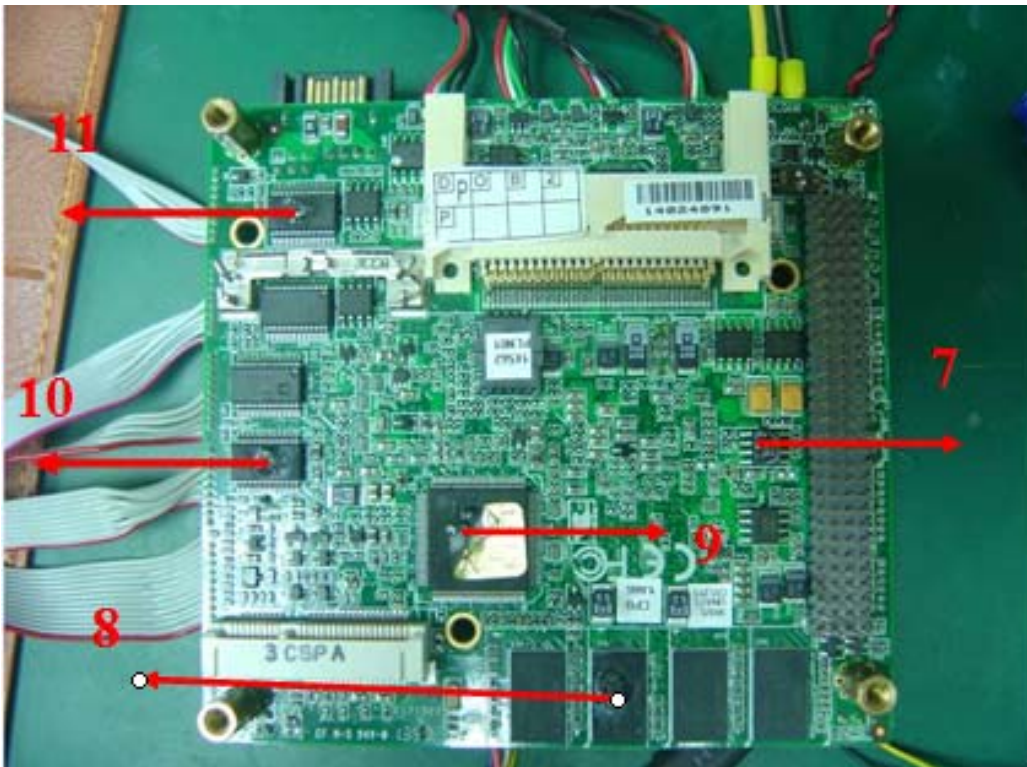
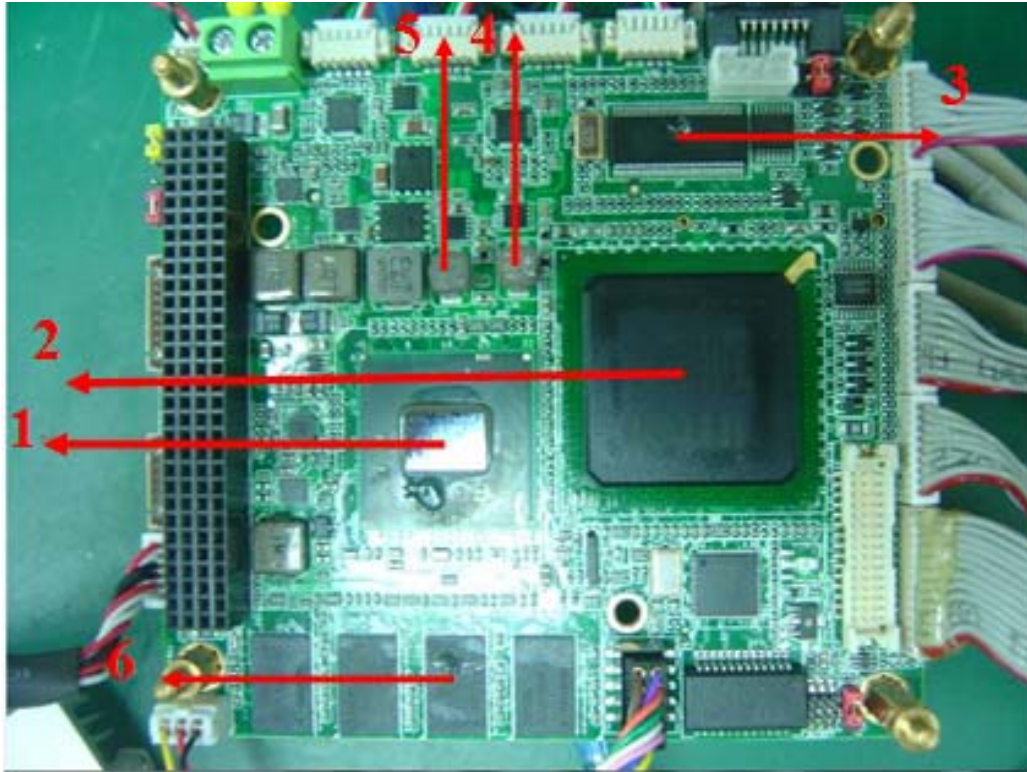
**After power on 2 hours**

**Temperature Profile Test:  
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Using YOKOGAWA / DARWIN DA100-100-13-1D test

Point	Position	Describe	Tc (*1) (°C)	Tm (*2) Measured Under		Note
				25°C	60°C	
1	U12	(TF)Intel CPU. AU80610004653AA SLBMG	100	43.8	78.8	
2	U6	(TF)IC.SMD.Chipset ICH8M.INTEL.DW82801HBM SLJ4Y	105	37.9	72.9	
3	U7	(TF)IC.SMD. 9LPRS501PGLF	115	36.0	71.0	
4	L34	(TF)COIL. NEC/TOKIN.MPLCG0530L3R3	120	39.8	74.8	
5	L33	(TF)COIL. NEC/TOKIN.MPLCG0530L2R2	120	38.6	73.6	
6	U11	Phase SAMSUNG.K4T1G164QF-BCE7	95	37.8	72.8	
7	U46	(TF)IC.SMD. Linear Regulator.GMT.G9731F11U	100	40.1	75.1	
8	U31	Phase.SAMSUNG.K4T1G164QF-BCE7	95	40.2	75.2	
9	U24	(TF)IC.SMD.VTQF-128Pin.Super I/O.SMSC.SCH3114-NU	85	40.1	75.1	
10	U18	(TF)IC.SMD.SSOP RS232 Driver ESD 15KV.AD.ADM213EARSZ	100	40.8	75.8	
11	U21	(TF)IC.SMD.SSOP RS232 Driver ESD 15KV.AD.ADM213EARSZ	100	39.6	74.6	

**Note(\*):**

1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
3. **Judgment Criteria:**
  - **Fail** : Tm > Tc+5°C; The measured value is over specification plus margin.
  - **Margin** : Tc+5°C > Tm > Tc-10°C; The measured value is within specification with margin.  
For FANLESS system application, it is strongly recommended to add thermal dissipation design for better reliability.
  - **Pass** : Tm < Tc-10°C; The measured value is with safety margin.
4. **Defect NO. :** [BUL1328LABE01](#)